

Notice of References Cited	Application/Control No. 10/678,910	Applicant(s)/Patent Under Reexamination CAHILL ET AL.	
	Examiner Shin-Hon Chen	Art Unit 2131	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0240763	10-2005	Bhat et al.	713/169
*	B	US-2004/0267870	12-2004	Rozmus et al.	709/200
*	C	US-2003/0149781	08-2003	Yared et al.	709/229
*	D	US-2004/0250140	12-2004	Chavis et al.	713/202
*	E	US-2003/0195858	10-2003	Watanabe et al.	705/75
*	F	US-2004/0210839	10-2004	Lucovsky, Mark H.	715/516
*	G	US-2004/0003112	01-2004	Alles et al.	709/237
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.